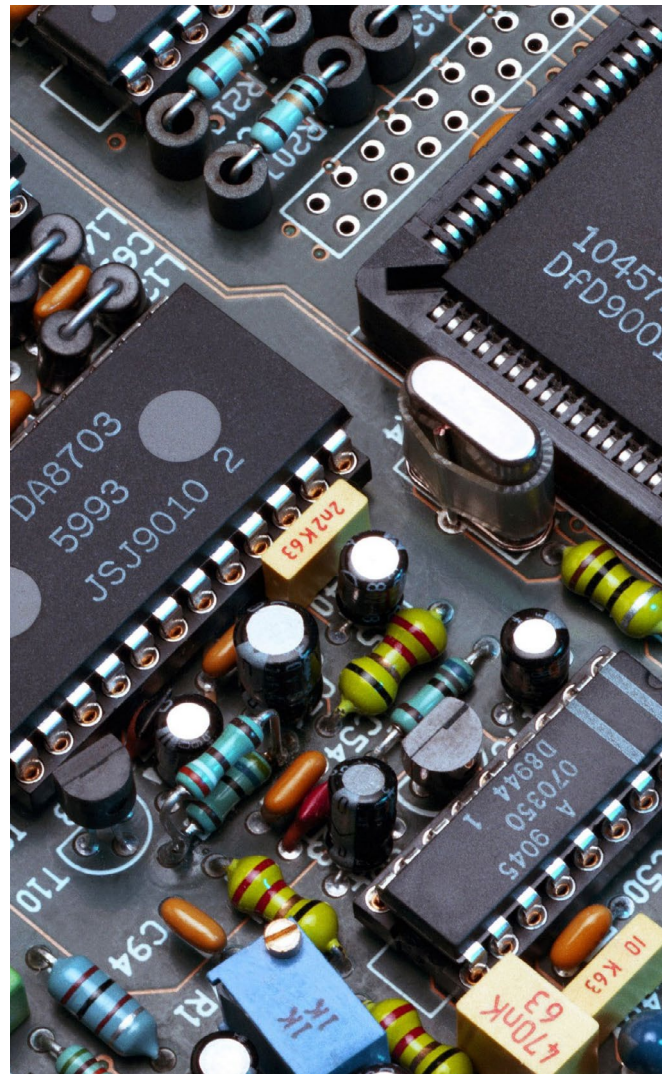
Fraunhofer Park
IMWS SYSTEMS
1 July
2021
International Symposium
Failure Analysis &
Material Testing
FAMT
2021

Fraunhofer IMWS and Park Systems are inviting for:

International Symposium:
Failure Analysis & Material Testing | FAMT 2021



Scope

Advancing miniaturization shapes our modern high-tech world. The design complexity of electronic components and the heterogeneity of new materials constantly increase with decreasing device sizes. New-engineered products need to secure a high level of reliability, sustainability, and longevity to meet international quality standards. Detection and classification of nanometer-sized material defects require characterization methods with a resolution in the nanometer range.

Who is addressed?

This symposium gathers the professionals from the electronic industry to discuss innovative testing methods at nanoscale and tools for physical failure analysis of the future.

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Sessions

- Case studies from the semiconductor device applications
- Innovative methods and tools for physical characterization of the material and defect review
- Emerging applications in the electronic industry
- Future methods for increasing line productivity, efficiency, and yield

Call for Abstracts

- Join us as an expert and present your application study
- Submit your ABSTRACT at www.parksystems.com/FAMT2021Symposium
- Deadline: June 1, 2021

The symposium is going to be held as a VIRTUAL EVENT on Zoom platform.

Access is free of charge.

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